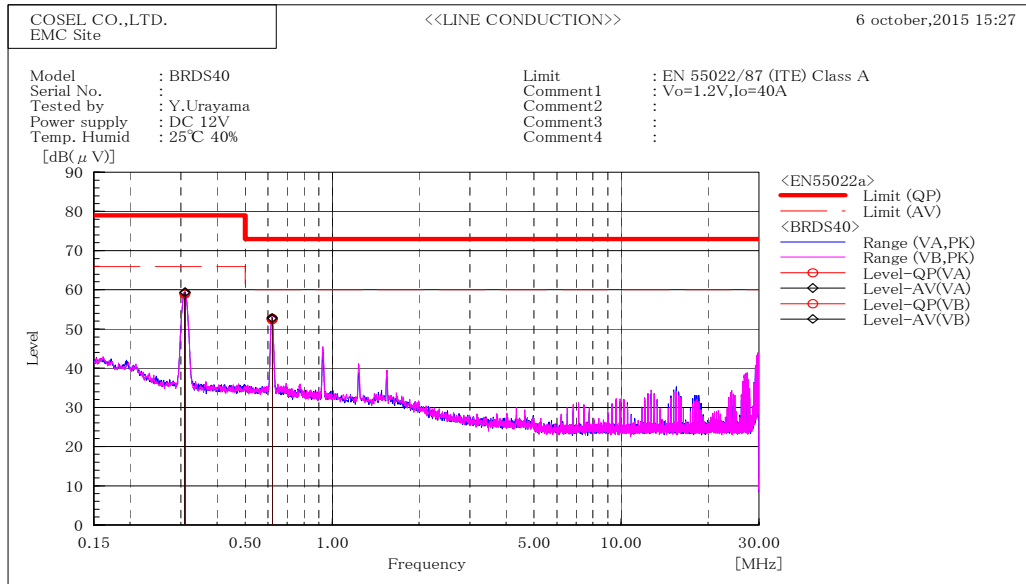
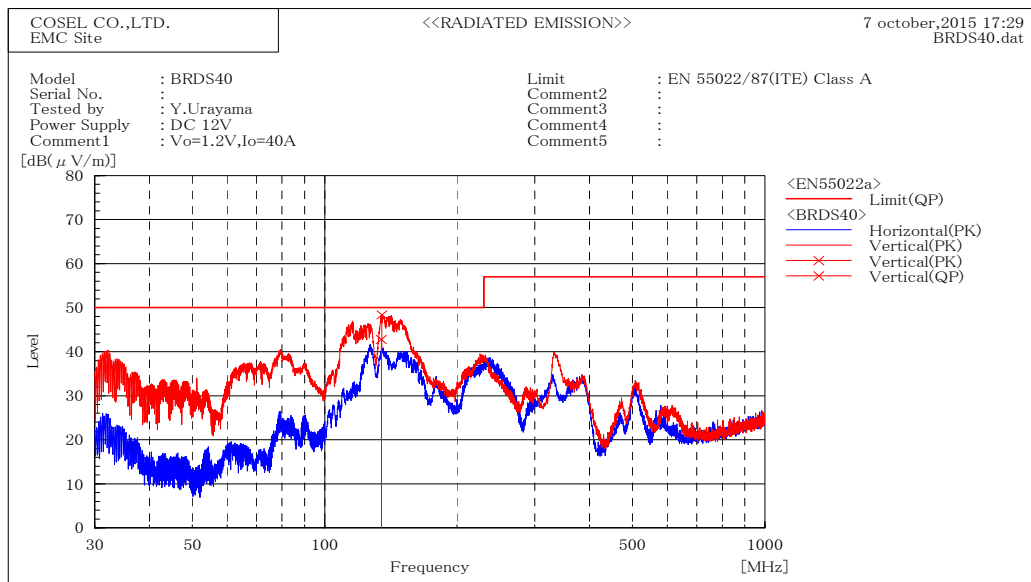


DATA SHEET		Date	06-Oct-15
Model	BRDS40	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Urayama



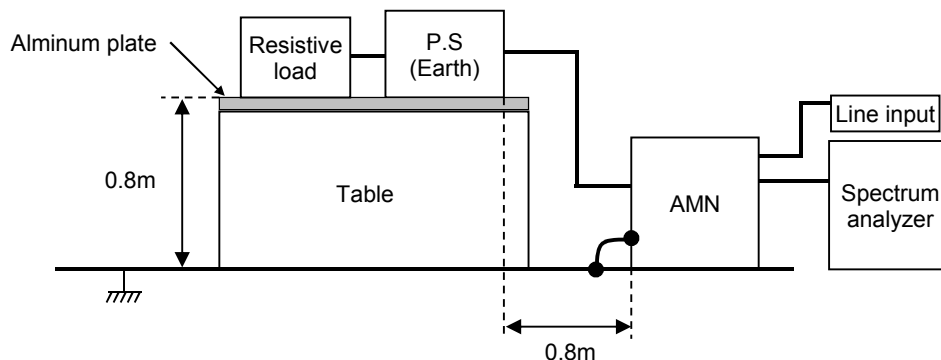
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.30937	VA	38.8	39.1	20.1	58.9	59.2	79	66	20.1	6.8	Pass	
0.30996	VB	39	39.3	20.1	59.1	59.4	79	66	19.9	6.6	Pass	
0.61991	VA	32.2	32.4	20.1	52.3	52.5	73	60	20.7	7.5	Pass	
0.62005	VB	32.6	32.7	20.1	52.7	52.8	73	60	20.3	7.2	Pass	



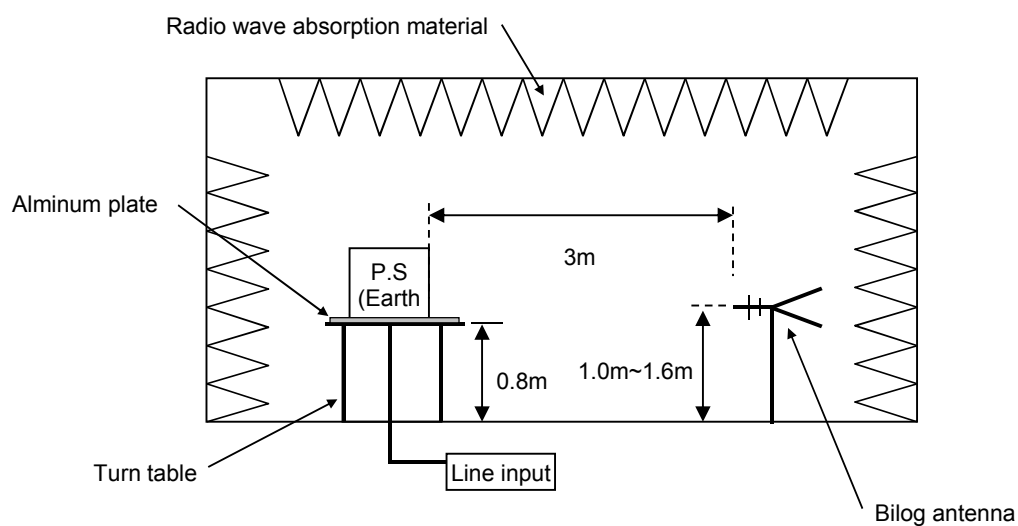
Frequency MHz	Polarization	Stability	Reading dB(μV)	Factor dB(1/m)	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
134.485	V	Stable	60.3	-17.5	42.8	50	7.2	Pass	103	51	

DATA SHEET		Date	06-Oct-15
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Urayama

## 1. Line conduction



## 2. Radiated emission

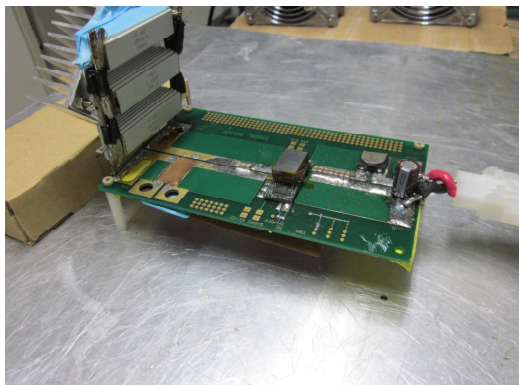


## Conditions

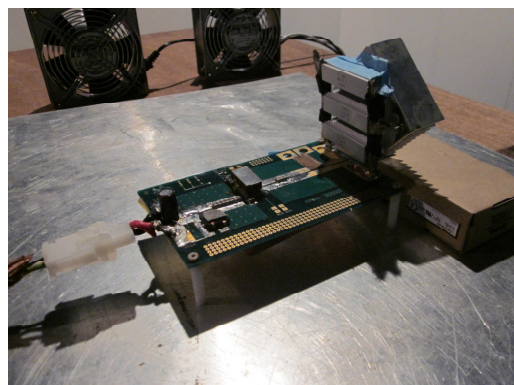
Test : EMI  
Model Name : BRDS40

○Photographs of Test Set-Up

### LINE CONDUCTION

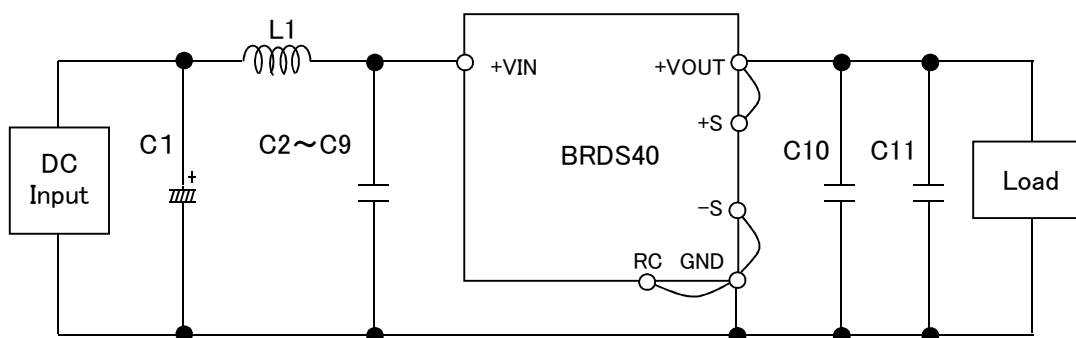


### RADIATED EMISSION



○Testing circuitry

○Test Circuit



C1	: 25V	470 $\mu$ F	Electrolytic capacitor
C2~C9	: 16V	22 $\mu$ F	Ceramic capacitor
C10 ,C11	: 6.3V	100 $\mu$ F	Ceramic capacitor
L1	: 0.3 $\mu$ H	ETQP2H0R3BFA	(Panasonic Electronics Devices)